JC20 Rec'd CT/PTO 0 9 MAY 2005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Kazuhiro Gono

Examiner:

Unassigned

Serial No.:

Unassigned

Art Unit:

Unassigned

Filed:

Herewith

Docket:

18871

For:

IMAGING APPARATUS

Dated:

May 9, 2005

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, it is requested that the following references, which are also listed on the attached Form PTO-1449, be made of record in the above-identified case.

- 1. Japanese Patent Application Publication No. 2002-034908, dated February 5, 2002, together with English-language Abstract;
- 2. Japanese Patent Application Publication No. 2002-095635, dated April 2, 2002, together with English-language Abstract;

CERTIFICATE OF MAILING BY EXPRESS MAIL

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I hereby certify that this correspondence is being deposited with the United States Postal Service Express Mail Post Office to Addressee service under 37 C.F.R. §1.10 on the date indicated above and is addressed to the Commissioner For Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Thomas Spinelli

- 3. Narihiro, Matoba et al., "Multispectral Image Capturing System", ITE Technical Report (2000), Vol. 24, No. 3, pp. 25-30;
- 4. Japanese Patent Application Publication No. 2002-034893, dated February 5, 2002, together with English-language Abstract;
- 5. Japanese Patent Application Publication No. 2003-527916, dated September 24, 2003, together with corresponding International PCT Patent Publication No. WO 01/72216 A2, dated October 4, 2001;
- 6. Japanese Patent Application Publication No. 2000-014629, dated January 18, 2000, together with English-language Abstract;
- 7. United States Patent Application Publication No. 2002/0135752 A1, issued to Sokolov et al., dated September 26, 2002;
- 8. Backman, Vadim, et al., "Polarized Light Scattering Spectroscopy for Quantitative Measurement of Epithelial Cellular Structures *In Situ*", IEEE Journal of Selected Topics in Quantum Electronics (1999), Vol. 5, No. 4, pp. 1019-1026; and
- 9. Japanese Patent Application Publication No. 2003-047588, dated February 18, 2003, together with English-language Abstract.

Reference numbers 1-7 were cited in the International Search Report of a corresponding International PCT Application. The relevance of reference numbers 1,2,4 and 8 has also been described in the specification. Applicant is submitting copies of the above-cited references, together with a copy of the Search Report. In accordance with the waiver of 37 C.F.R. § 1.98 (a)(2)(i) in effect as of June 30, 2003, applicant is not required to submit a copy of the above-cited U.S. Patent reference.

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Inasmuch as this Information Disclosure Statement is being submitted in accordance with

the schedule set out in 37 C.F.R. § 1.97(b), no statement or fee is required.

Respectfully submitted

Thomas Spinelli

Registration No. 39,533

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TS:jam

INFORMATION DISCLOSUS ITATION (Use several sheets if necessary)

Applicant(s)

Kazuhiro Gono

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	-		U.S.	PATENT DOCUMENTS					
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME				NG DATE ROPRIATE	
		2002/0135752 A1	9/26/2002	Sokolov et al.					
	-		FOREIG	N PATENT DOCUMENT	rs				
							TRANSLATION		
	REF	DOCUMENT NUMBER	. DATE	COUNTRY	CLASS	SUBCLASS	YES	NO	
		2002-034908	2/5/2002	Japan					
		2002-095635	4/2/2002	Japan					
		2002-034893	2/5/2002	Japan					
		2003-527916	9/24/2003	Japan	. ,.				
		WO 01/72216 A2	10/4/2001	PCT					
		2000-014629	1/18/2000	Japan					
		2003-047588	2/18/2003	Japan					
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		OTHER DOCU	JMENTS (Incl	uding Author, Title, Date,	Pertinent Pages	, Etc.)			
				ispectral Image Captur 24, No. 3, pp. 25-30	ing System", I	TE		-	
		Measurement of I	Epithelial Cel	rized Light Scattering S lular Structures <i>In Situ</i> Vol. 5, No. 4, pp. 1019-1	ı", IEEE Journ			in (
EXAMINER	-	<u> </u>		DATE CONSID	DATE CONSIDERED				

Form PTO-A820 U.S. DEPARTMENT OF COMMERCE (also form PTO-1449) P09A/REV04

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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